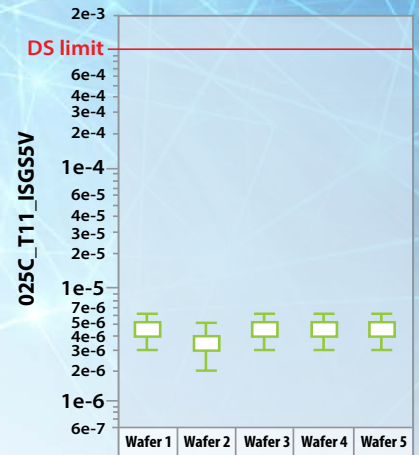




# GaN Device Test Information

EPC has partnered with **Spirit Electronics** to provide an expanded range of manufacturing lot specific data services. The below table details the services available. If you have specific requirements not addressed in the table below, please contact us at [info@epc-co.com](mailto:info@epc-co.com)

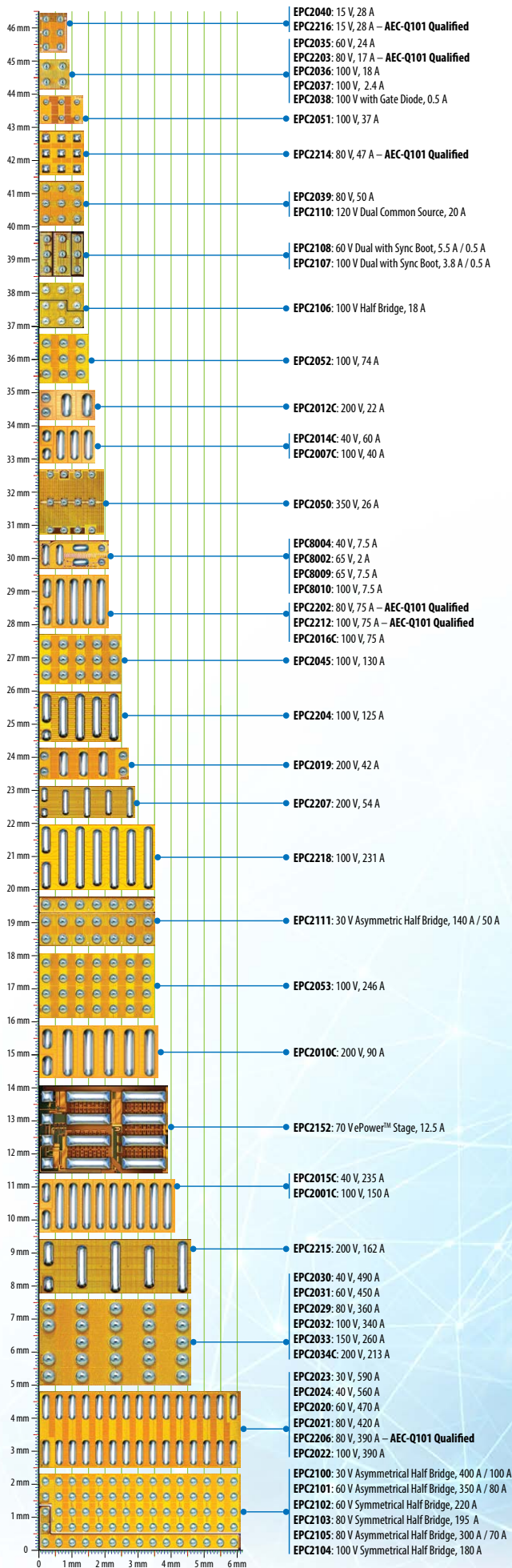
Variability Gauge  
Variability Chart for 025C\_T11\_ISGS5V



## Data Pack Offering for EPC Commercial Devices

Data Pack	Description	Test Parameter	Data Type	Temperature
<b>Lot Data Pack</b>	Lot on tape and reel. Data pack of electrical distribution for the lot (mean, standard deviation, min, max).	$I_{DSS}$ (Drain-Source Leakage)	Mean, Std Dev, Min, Max	25°C
		$I_{GSS5V}$ (Gate-to-Source Forward Leakage)		
		$I_{GSSmV}$ (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
<b>Serialized Lot Data Pack</b>	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, 25°C data.	$I_{DSS}$ (Drain-Source Leakage)	Serialized Read & Record	25°C
		$I_{GSS5V}$ (Gate-to-Source Forward Leakage)		
		$I_{GSSmV}$ (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
<b>Serialized Lot Data Pack - HighTemp</b>	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, 150°C data.	$I_{DSS}$ (Drain-Source Leakage)	Serialized Read & Record	150°C
		$I_{GSS5V}$ (Gate-to-Source Forward Leakage)		
		$I_{GSSmV}$ (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
<b>Serialized Lot Data Pack - LowTemp</b>	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, -55°C data.	$I_{DSS}$ (Drain-Source Leakage)	Serialized Read & Record	-55°C
		$I_{GSS5V}$ (Gate-to-Source Forward Leakage)		
		$I_{GSSmV}$ (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
<b>Serialized Lot Data Pack with Visual</b>	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, 25°C data. Die visual inspection sample data.	$I_{DSS}$ (Drain-Source Leakage)	Serialized Read & Record	25°C
		$I_{GSS5V}$ (Gate-to-Source Forward Leakage)		
		$I_{GSSmV}$ (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
		Visual Inspection Sample Data	Serialized Photo Records	N/A
<b>Serialized Lot Data Pack with Visual - HighTemp</b>	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, 150°C data. Die visual inspection sample data.	$I_{DSS}$ (Drain-Source Leakage)	Serialized Read & Record	150°C
		$I_{GSS5V}$ (Gate-to-Source Forward Leakage)		
		$I_{GSSmV}$ (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
		Visual Inspection Sample Data	Serialized Photo Records	N/A
<b>Serialized Lot Data Pack with Visual - LowTemp</b>	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, -55°C data. Die visual inspection sample data.	$I_{DSS}$ (Drain-Source Leakage)	Serialized Read & Record	-55°C
		$I_{GSS5V}$ (Gate-to-Source Forward Leakage)		
		$I_{GSSmV}$ (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
		Visual Inspection Sample Data	Serialized Photo Records	N/A

For information on pricing and availability please contact [Spirit Electronics](http://www.spirit-electronics.com)



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